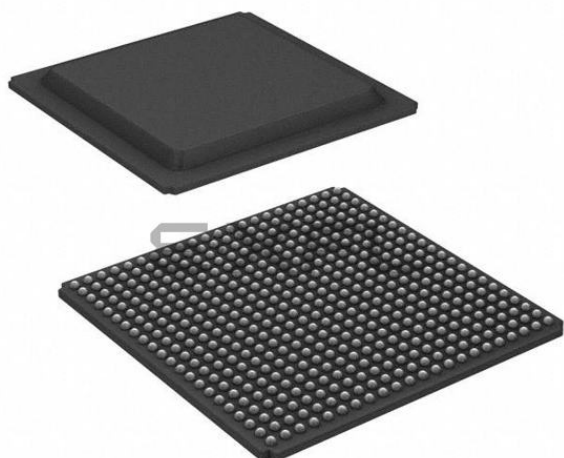




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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

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The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	7911
Number of Logic Elements/Cells	101261
Total RAM Bits	4939776
Number of I/O	326
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	484-BBGA
Supplier Device Package	484-FBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6slx100-n3fg484i

Table 1: Absolute Maximum Ratings⁽¹⁾ (Cont'd)

Symbol	Description					Units
V_{IN} and V_{TS} ⁽³⁾	I/O input voltage or voltage applied to 3-state output, relative to GND ⁽⁴⁾	All user and dedicated I/Os	Commercial	DC	–0.60 to 4.10	V
				20% overshoot duration	–0.75 to 4.25	V
				8% overshoot duration ⁽⁵⁾	–0.75 to 4.40	V
			Industrial	DC	–0.60 to 3.95	V
				20% overshoot duration	–0.75 to 4.15	V
				4% overshoot duration ⁽⁵⁾	–0.75 to 4.40	V
			Expanded (Q)	DC	–0.60 to 3.95	V
				20% overshoot duration	–0.75 to 4.15	V
				4% overshoot duration ⁽⁵⁾	–0.75 to 4.40	V
		Restricted to maximum of 100 user I/Os	Commercial	20% overshoot duration	–0.75 to 4.35	V
				15% overshoot duration ⁽⁵⁾	–0.75 to 4.40	V
				10% overshoot duration	–0.75 to 4.45	V
			Industrial	20% overshoot duration	–0.75 to 4.25	V
				10% overshoot duration	–0.75 to 4.35	V
				8% overshoot duration ⁽⁵⁾	–0.75 to 4.40	V
			Expanded (Q)	20% overshoot duration	–0.75 to 4.25	V
				10% overshoot duration	–0.75 to 4.35	V
				8% overshoot duration ⁽⁵⁾	–0.75 to 4.40	V
T_{STG}	Storage temperature (ambient)				–65 to 150	°C
T_{SOL}	Maximum soldering temperature ⁽⁶⁾ (TQG144, CPG196, CSG225, CSG324, CSG484, and FTG256)				+260	°C
	Maximum soldering temperature ⁽⁶⁾ (Pb-free packages: FGG484, FGG676, and FGG900)				+250	°C
	Maximum soldering temperature ⁽⁶⁾ (Pb packages: CS484, FT256, FG484, FG676, and FG900)				+220	°C
T_j	Maximum junction temperature ⁽⁶⁾				+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.
- When programming eFUSE, $V_{FS} \leq V_{CCAUX}$. Requires up to 40 mA current. For read mode, V_{FS} can be between GND and 3.45 V.
- I/O absolute maximum limit applied to DC and AC signals. Overshoot duration is the percentage of a data period that the I/O is stressed beyond 3.45V.
- For I/O operation, refer to [UG381](#): *Spartan-6 FPGA SelectIO Resources User Guide*.
- Maximum percent overshoot duration to meet 4.40V maximum.
- For soldering guidelines and thermal considerations, see [UG385](#): *Spartan-6 FPGA Packaging and Pinout Specification*.

Table 3: eFUSE Programming Conditions⁽¹⁾

Symbol	Description	Min	Typ	Max	Units
$V_{FS}^{(2)}$	External voltage supply	3.2	3.3	3.4	V
I_{FS}	V_{FS} supply current	–	–	40	mA
V_{CCAUX}	Auxiliary supply voltage relative to GND	3.2	3.3	3.45	V
$R_{FUSE}^{(3)}$	External resistor from R_{FUSE} pin to GND	1129	1140	1151	Ω
V_{CCINT}	Internal supply voltage relative to GND	1.14	1.2	1.26	V
t_j	Temperature range	15	–	85	$^{\circ}\text{C}$

Notes:

1. These specifications apply during programming of the eFUSE AES key. Programming is only supported through JTAG. The AES key is only supported in the following devices: LX75, LX75T, LX100, LX100T, LX150, and LX150T.
2. When programming eFUSE, V_{FS} must be less than or equal to V_{CCAUX} . When not programming or when eFUSE is not used, Xilinx recommends connecting V_{FS} to GND. However, V_{FS} can be between GND and 3.45 V.
3. An R_{FUSE} resistor is required when programming the eFUSE AES key. When not programming or when eFUSE is not used, Xilinx recommends connecting the R_{FUSE} pin to V_{CCAUX} or GND. However, R_{FUSE} can be unconnected.

In Table 9 and Table 10, values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum V_{CCO} with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Table 9: Single-Ended I/O Standard DC Input and Output Levels

I/O Standard	V_{IL}		V_{IH}		V_{OL}	V_{OH}	I_{OL}	I_{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
LVTTTL	−0.5	0.8	2.0	4.1	0.4	2.4	Note 2	Note 2
LVC MOS33	−0.5	0.8	2.0	4.1	0.4	$V_{CCO} - 0.4$	Note 2	Note 2
LVC MOS25	−0.5	0.7	1.7	4.1	0.4	$V_{CCO} - 0.4$	Note 2	Note 2
LVC MOS18	−0.5	0.38	0.8	4.1	0.45	$V_{CCO} - 0.45$	Note 2	Note 2
LVC MOS18 (−1L)	−0.5	0.33	0.71	4.1	0.45	$V_{CCO} - 0.45$	Note 2	Note 2
LVC MOS18_JEDEC	−0.5	35% V_{CCO}	65% V_{CCO}	4.1	0.45	$V_{CCO} - 0.45$	Note 2	Note 2
LVC MOS15	−0.5	0.38	0.8	4.1	25% V_{CCO}	75% V_{CCO}	Note 3	Note 3
LVC MOS15 (−1L)	−0.5	0.33	0.71	4.1	25% V_{CCO}	75% V_{CCO}	Note 3	Note 3
LVC MOS15_JEDEC	−0.5	35% V_{CCO}	65% V_{CCO}	4.1	25% V_{CCO}	75% V_{CCO}	Note 3	Note 3
LVC MOS12	−0.5	0.38	0.8	4.1	0.4	$V_{CCO} - 0.4$	Note 4	Note 4
LVC MOS12 (−1L)	−0.5	0.33	0.71	4.1	0.4	$V_{CCO} - 0.4$	Note 4	Note 4
LVC MOS12_JEDEC	−0.5	35% V_{CCO}	65% V_{CCO}	4.1	0.4	$V_{CCO} - 0.4$	Note 4	Note 4
PCI33_3	−0.5	30% V_{CCO}	50% V_{CCO}	$V_{CCO} + 0.5$	10% V_{CCO}	90% V_{CCO}	1.5	−0.5
PCI66_3	−0.5	30% V_{CCO}	50% V_{CCO}	$V_{CCO} + 0.5$	10% V_{CCO}	90% V_{CCO}	1.5	−0.5
I2C	−0.5	25% V_{CCO}	70% V_{CCO}	4.1	20% V_{CCO}	—	3	—
SMBUS	−0.5	0.8	2.1	4.1	0.4	—	4	—
SDIO	−0.5	12.5% V_{CCO}	75% V_{CCO}	4.1	12.5% V_{CCO}	75% V_{CCO}	0.1	−0.1
MOBILE_DDR	−0.5	20% V_{CCO}	80% V_{CCO}	4.1	10% V_{CCO}	90% V_{CCO}	0.1	−0.1
HSTL_I	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	0.4	$V_{CCO} - 0.4$	8	−8
HSTL_II	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	0.4	$V_{CCO} - 0.4$	16	−16
HSTL_III	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	0.4	$V_{CCO} - 0.4$	24	−8
HSTL_I_18	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	0.4	$V_{CCO} - 0.4$	11	−11
HSTL_II_18	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	0.4	$V_{CCO} - 0.4$	22	−22
HSTL_III_18	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	0.4	$V_{CCO} - 0.4$	30	−11
SSTL3_I	−0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	4.1	$V_{TT} - 0.6$	$V_{TT} + 0.6$	8	−8
SSTL3_II	−0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	4.1	$V_{TT} - 0.8$	$V_{TT} + 0.8$	16	−16
SSTL2_I	−0.5	$V_{REF} - 0.15$	$V_{REF} + 0.15$	4.1	$V_{TT} - 0.61$	$V_{TT} + 0.61$	8.1	−8.1
SSTL2_II	−0.5	$V_{REF} - 0.15$	$V_{REF} + 0.15$	4.1	$V_{TT} - 0.81$	$V_{TT} + 0.81$	16.2	−16.2
SSTL18_I	−0.5	$V_{REF} - 0.125$	$V_{REF} + 0.125$	4.1	$V_{TT} - 0.47$	$V_{TT} + 0.47$	6.7	−6.7
SSTL18_II	−0.5	$V_{REF} - 0.125$	$V_{REF} + 0.125$	4.1	$V_{TT} - 0.60$	$V_{TT} + 0.60$	13.4	−13.4
SSTL15_II	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	$V_{TT} - 0.4$	$V_{TT} + 0.4$	13.4	−13.4

Notes:

1. Tested according to relevant specifications.
2. Using drive strengths of 2, 4, 6, 8, 12, 16, or 24 mA.
3. Using drive strengths of 2, 4, 6, 8, 12, or 16 mA.
4. Using drive strengths of 2, 4, 6, 8, or 12 mA.
5. For more information, refer to [UG381](#): *Spartan-6 FPGA SelectIO Resources User Guide*.

Table 28: IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	
LVC MOS15, Slow, 8 mA	0.98	1.10	1.23	1.79	2.30	2.44	2.64	3.25	2.30	2.44	2.64	3.25	ns
LVC MOS15, Slow, 12 mA	0.98	1.10	1.23	1.79	2.03	2.17	2.37	2.99	2.03	2.17	2.37	2.99	ns
LVC MOS15, Slow, 16 mA	0.98	1.10	1.23	1.79	2.01	2.15	2.35	2.97	2.01	2.15	2.35	2.97	ns
LVC MOS15, Fast, 2 mA	0.98	1.10	1.23	1.79	3.29	3.43	3.63	4.24	3.29	3.43	3.63	4.24	ns
LVC MOS15, Fast, 4 mA	0.98	1.10	1.23	1.79	2.27	2.41	2.61	3.22	2.27	2.41	2.61	3.22	ns
LVC MOS15, Fast, 6 mA	0.98	1.10	1.23	1.79	1.78	1.92	2.12	2.74	1.78	1.92	2.12	2.74	ns
LVC MOS15, Fast, 8 mA	0.98	1.10	1.23	1.79	1.73	1.87	2.07	2.69	1.73	1.87	2.07	2.69	ns
LVC MOS15, Fast, 12 mA	0.98	1.10	1.23	1.79	1.73	1.87	2.07	2.64	1.73	1.87	2.07	2.64	ns
LVC MOS15, Fast, 16 mA	0.98	1.10	1.23	1.79	1.73	1.87	2.07	2.64	1.73	1.87	2.07	2.64	ns
LVC MOS15_JEDEC, QUIETIO, 2 mA	1.03	1.15	1.28	1.49	5.49	5.63	5.83	6.37	5.49	5.63	5.83	6.37	ns
LVC MOS15_JEDEC, QUIETIO, 4 mA	1.03	1.15	1.28	1.49	4.61	4.75	4.95	5.51	4.61	4.75	4.95	5.51	ns
LVC MOS15_JEDEC, QUIETIO, 6 mA	1.03	1.15	1.28	1.49	4.07	4.21	4.41	4.97	4.07	4.21	4.41	4.97	ns
LVC MOS15_JEDEC, QUIETIO, 8 mA	1.03	1.15	1.28	1.49	3.92	4.06	4.26	4.81	3.92	4.06	4.26	4.81	ns
LVC MOS15_JEDEC, QUIETIO, 12 mA	1.03	1.15	1.28	1.49	3.54	3.68	3.88	4.51	3.54	3.68	3.88	4.51	ns
LVC MOS15_JEDEC, QUIETIO, 16 mA	1.03	1.15	1.28	1.49	3.33	3.47	3.67	4.31	3.33	3.47	3.67	4.31	ns
LVC MOS15_JEDEC, Slow, 2 mA	1.03	1.15	1.28	1.49	4.18	4.32	4.52	5.13	4.18	4.32	4.52	5.13	ns
LVC MOS15_JEDEC, Slow, 4 mA	1.03	1.15	1.28	1.49	3.42	3.56	3.76	4.35	3.42	3.56	3.76	4.35	ns
LVC MOS15_JEDEC, Slow, 6 mA	1.03	1.15	1.28	1.49	2.29	2.43	2.63	3.25	2.29	2.43	2.63	3.25	ns
LVC MOS15_JEDEC, Slow, 8 mA	1.03	1.15	1.28	1.49	2.30	2.44	2.64	3.26	2.30	2.44	2.64	3.26	ns
LVC MOS15_JEDEC, Slow, 12 mA	1.03	1.15	1.28	1.49	2.01	2.15	2.35	2.97	2.01	2.15	2.35	2.97	ns
LVC MOS15_JEDEC, Slow, 16 mA	1.03	1.15	1.28	1.49	2.01	2.15	2.35	2.97	2.01	2.15	2.35	2.97	ns
LVC MOS15_JEDEC, Fast, 2 mA	1.03	1.15	1.28	1.49	3.28	3.42	3.62	4.22	3.28	3.42	3.62	4.22	ns
LVC MOS15_JEDEC, Fast, 4 mA	1.03	1.15	1.28	1.49	2.27	2.41	2.61	3.23	2.27	2.41	2.61	3.23	ns
LVC MOS15_JEDEC, Fast, 6 mA	1.03	1.15	1.28	1.49	1.78	1.92	2.12	2.74	1.78	1.92	2.12	2.74	ns
LVC MOS15_JEDEC, Fast, 8 mA	1.03	1.15	1.28	1.49	1.73	1.87	2.07	2.69	1.73	1.87	2.07	2.69	ns
LVC MOS15_JEDEC, Fast, 12 mA	1.03	1.15	1.28	1.49	1.73	1.87	2.07	2.63	1.73	1.87	2.07	2.63	ns
LVC MOS15_JEDEC, Fast, 16 mA	1.03	1.15	1.28	1.49	1.73	1.87	2.07	2.63	1.73	1.87	2.07	2.63	ns
LVC MOS12, QUIETIO, 2 mA	0.91	1.03	1.16	1.51	6.40	6.54	6.74	7.30	6.40	6.54	6.74	7.30	ns
LVC MOS12, QUIETIO, 4 mA	0.91	1.03	1.16	1.51	4.98	5.12	5.32	5.90	4.98	5.12	5.32	5.90	ns
LVC MOS12, QUIETIO, 6 mA	0.91	1.03	1.16	1.51	4.65	4.79	4.99	5.55	4.65	4.79	4.99	5.55	ns
LVC MOS12, QUIETIO, 8 mA	0.91	1.03	1.16	1.51	4.23	4.37	4.57	5.21	4.23	4.37	4.57	5.21	ns
LVC MOS12, QUIETIO, 12 mA	0.91	1.03	1.16	1.51	3.98	4.12	4.32	4.94	3.98	4.12	4.32	4.94	ns
LVC MOS12, Slow, 2 mA	0.91	1.03	1.16	1.51	4.98	5.12	5.32	5.91	4.98	5.12	5.32	5.91	ns
LVC MOS12, Slow, 4 mA	0.91	1.03	1.16	1.51	2.84	2.98	3.18	3.81	2.84	2.98	3.18	3.81	ns
LVC MOS12, Slow, 6 mA	0.91	1.03	1.16	1.51	2.77	2.91	3.11	3.72	2.77	2.91	3.11	3.72	ns
LVC MOS12, Slow, 8 mA	0.91	1.03	1.16	1.51	2.34	2.48	2.68	3.31	2.34	2.48	2.68	3.31	ns
LVC MOS12, Slow, 12 mA	0.91	1.03	1.16	1.51	2.08	2.22	2.42	3.06	2.08	2.22	2.42	3.06	ns

Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices⁽¹⁾ (Cont'd)

I/O Standard	T _{IOPI}		T _{IOOP}		T _{IOTP}		Units
	Speed Grade		Speed Grade		Speed Grade		
	-3	-2	-3	-2	-3	-2	
LVC MOS18, QUIETIO, 16 mA	1.25	1.43	3.34	3.54	3.34	3.54	ns
LVC MOS18, QUIETIO, 24 mA	1.25	1.43	3.18	3.38	3.18	3.38	ns
LVC MOS18, Slow, 2 mA	1.25	1.43	4.79	4.99	4.79	4.99	ns
LVC MOS18, Slow, 4 mA	1.25	1.43	3.84	4.04	3.84	4.04	ns
LVC MOS18, Slow, 6 mA	1.25	1.43	3.17	3.37	3.17	3.37	ns
LVC MOS18, Slow, 8 mA	1.25	1.43	2.37	2.57	2.37	2.57	ns
LVC MOS18, Slow, 12 mA	1.25	1.43	2.13	2.33	2.13	2.33	ns
LVC MOS18, Slow, 16 mA	1.25	1.43	2.13	2.33	2.13	2.33	ns
LVC MOS18, Slow, 24 mA	1.25	1.43	2.13	2.33	2.13	2.33	ns
LVC MOS18, Fast, 2 mA	1.25	1.43	3.78	3.98	3.78	3.98	ns
LVC MOS18, Fast, 4 mA	1.25	1.43	2.54	2.74	2.54	2.74	ns
LVC MOS18, Fast, 6 mA	1.25	1.43	2.02	2.22	2.02	2.22	ns
LVC MOS18, Fast, 8 mA	1.25	1.43	1.95	2.15	1.95	2.15	ns
LVC MOS18, Fast, 12 mA	1.25	1.43	1.85	2.05	1.85	2.05	ns
LVC MOS18, Fast, 16 mA	1.25	1.43	1.85	2.05	1.85	2.05	ns
LVC MOS18, Fast, 24 mA	1.25	1.43	1.85	2.05	1.85	2.05	ns
LVC MOS18_JEDEC, QUIETIO, 2 mA	1.01	1.19	6.09	6.29	6.09	6.29	ns
LVC MOS18_JEDEC, QUIETIO, 4 mA	1.01	1.19	4.89	5.09	4.89	5.09	ns
LVC MOS18_JEDEC, QUIETIO, 6 mA	1.01	1.19	4.20	4.40	4.20	4.40	ns
LVC MOS18_JEDEC, QUIETIO, 8 mA	1.01	1.19	3.87	4.07	3.87	4.07	ns
LVC MOS18_JEDEC, QUIETIO, 12 mA	1.01	1.19	3.49	3.69	3.49	3.69	ns
LVC MOS18_JEDEC, QUIETIO, 16 mA	1.01	1.19	3.34	3.54	3.34	3.54	ns
LVC MOS18_JEDEC, QUIETIO, 24 mA	1.01	1.19	3.17	3.37	3.17	3.37	ns
LVC MOS18_JEDEC, Slow, 2 mA	1.01	1.19	4.79	4.99	4.79	4.99	ns
LVC MOS18_JEDEC, Slow, 4 mA	1.01	1.19	3.84	4.04	3.84	4.04	ns
LVC MOS18_JEDEC, Slow, 6 mA	1.01	1.19	3.18	3.38	3.18	3.38	ns
LVC MOS18_JEDEC, Slow, 8 mA	1.01	1.19	2.37	2.57	2.37	2.57	ns
LVC MOS18_JEDEC, Slow, 12 mA	1.01	1.19	2.13	2.33	2.13	2.33	ns
LVC MOS18_JEDEC, Slow, 16 mA	1.01	1.19	2.13	2.33	2.13	2.33	ns
LVC MOS18_JEDEC, Slow, 24 mA	1.01	1.19	2.13	2.33	2.13	2.33	ns
LVC MOS18_JEDEC, Fast, 2 mA	1.01	1.19	3.75	3.95	3.75	3.95	ns
LVC MOS18_JEDEC, Fast, 4 mA	1.01	1.19	2.54	2.74	2.54	2.74	ns
LVC MOS18_JEDEC, Fast, 6 mA	1.01	1.19	2.02	2.22	2.02	2.22	ns
LVC MOS18_JEDEC, Fast, 8 mA	1.01	1.19	1.94	2.14	1.94	2.14	ns
LVC MOS18_JEDEC, Fast, 12 mA	1.01	1.19	1.86	2.06	1.86	2.06	ns
LVC MOS18_JEDEC, Fast, 16 mA	1.01	1.19	1.86	2.06	1.86	2.06	ns
LVC MOS18_JEDEC, Fast, 24 mA	1.01	1.19	1.86	2.06	1.86	2.06	ns

Output Delay Measurements

Output delays are measured using a Tektronix P6245 TDS500/600 probe (< 1 pF) across approximately 4" of FR4 microstrip trace. Standard termination was used for all testing. The propagation delay of the 4" trace is characterized separately and subtracted from the final measurement, and is therefore not included in the generalized test setups shown in Figure 4 and Figure 5.

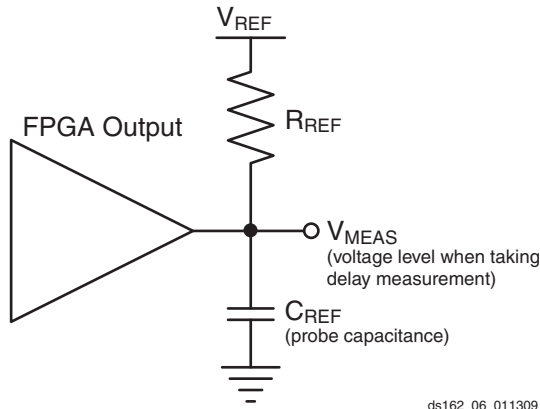
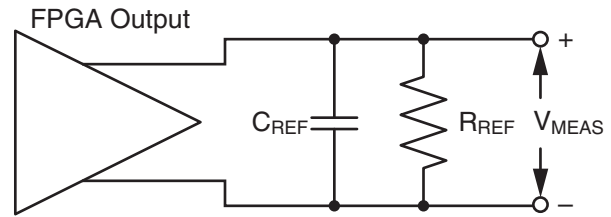


Figure 4: Single-Ended Test Setup



ds162_07_011309

Figure 5: Differential Test Setup

Measurements and test conditions are reflected in the IBIS models except where the IBIS format precludes it. Parameters V_{REF} , R_{REF} , C_{REF} , and V_{MEAS} fully describe the test conditions for each I/O standard. The most accurate prediction of propagation delay in any given application can be obtained through IBIS simulation, using the following method:

1. Simulate the output driver of choice into the generalized test setup, using values from Table 32.
2. Record the time to V_{MEAS} .
3. Simulate the output driver of choice into the actual PCB trace and load, using the appropriate IBIS model or capacitance value to represent the load.
4. Record the time to V_{MEAS} .
5. Compare the results of steps 2 and 4. The increase or decrease in delay yields the actual propagation delay of the PCB trace.

Table 32: Output Delay Measurement Methodology

Description	I/O Standard Attribute	R_{REF} (Ω)	$C_{REF}^{(1)}$ (pF)	V_{MEAS} (V)	V_{REF} (V)
LVTTTL (Low-Voltage Transistor-Transistor Logic)	LVTTTL (all)	1M	0	1.4	0
LVC MOS (Low-Voltage CMOS), 3.3V	LVC MOS33	1M	0	1.65	0
LVC MOS, 2.5V	LVC MOS25	1M	0	1.25	0
LVC MOS, 1.8V	LVC MOS18	1M	0	0.9	0
LVC MOS, 1.5V	LVC MOS15	1M	0	0.75	0
LVC MOS, 1.2V	LVC MOS12	1M	0	0.6	0
PCI (Peripheral Component Interface) 33 MHz and 66 MHz, 3.3V	PCI33_3, PCI66_3 (rising edge)	25	10 ⁽²⁾	0.94	0
	PCI33_3, PCI66_3 (falling edge)	25	10 ⁽²⁾	2.03	3.3
HSTL (High-Speed Transceiver Logic), Class I	HSTL_I	50	0	V_{REF}	0.75
HSTL, Class II	HSTL_II	25	0	V_{REF}	0.75
HSTL, Class III	HSTL_III	50	0	0.9	1.5
HSTL, Class I, 1.8V	HSTL_I_18	50	0	V_{REF}	0.9
HSTL, Class II, 1.8V	HSTL_II_18	25	0	V_{REF}	0.9
HSTL, Class III, 1.8V	HSTL_III_18	50	0	1.1	1.8
SSTL (Stub Series Terminated Logic), Class I, 1.8V	SSTL18_I	50	0	V_{REF}	0.9
SSTL, Class II, 1.8V	SSTL18_II	25	0	V_{REF}	0.9
SSTL, Class I, 2.5V	SSTL2_I	50	0	V_{REF}	1.25

Table 34: SSO Limit per V_{CCO}/GND Pair (Cont'd)

V _{CCO}	I/O Standard	Drive	Slew	SSO Limit per V _{CCO} /GND Pair					
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324			
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5		
2.5V	LVCMOS25	2	Fast	38	43	38	43		
			Slow	46	52	46	48		
			QuietIO	57	64	57	59		
		4	Fast	21	24	21	23		
			Slow	26	31	26	27		
			QuietIO	33	32	33	30		
		6	Fast	15	17	15	16		
			Slow	19	22	19	19		
			QuietIO	25	23	25	19		
		8	Fast	12	15	12	14		
			Slow	15	18	15	16		
			QuietIO	21	19	21	16		
		12	Fast	1	3	1	1		
			Slow	2	7	2	4		
			QuietIO	3	8	3	8		
		16	Fast	1	3	1	1		
			Slow	3	7	3	3		
			QuietIO	4	9	4	8		
		24	Fast	N/A	3	N/A	1		
			Slow	N/A	5	N/A	2		
			QuietIO	N/A	8	N/A	6		
		SSTL_2_I ⁽³⁾				10	11	10	11
		SSTL_2_II ⁽³⁾				N/A	7	N/A	7
		DIFF_SSTL_2_I ⁽³⁾				30	33	30	33
	DIFF_SSTL_2_II ⁽³⁾				N/A	21	N/A	24	

Table 34: SSO Limit per V_{CCO}/GND Pair (Cont'd)

V_{CCO}	I/O Standard	Drive	Slew	SSO Limit per V_{CCO}/GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
Various	LVDS_33			16	N/A	16	N/A
	LVDS_25			20	N/A	20	N/A
	BLVDS_25			20	48	20	20
	MINI_LVDS_33			13	N/A	13	N/A
	MINI_LVDS_25			18	N/A	18	N/A
	RSDS_33			12	N/A	12	N/A
	RSDS_25			15	N/A	15	N/A
	TMDS_33			83	N/A	83	N/A
	PPDS_33			12	N/A	12	N/A
	PPDS_25			16	N/A	16	N/A
	DISPLAY_PORT			42	40	42	30
	I2C			47	55	47	42
	SMBUS			44	52	44	40

Notes:

- SSO limits greater than the number of I/O per V_{CCO}/GND pair (Table 33) indicate No Limit for the given I/O standard. They are provided in this table to calculate limits when using multiple I/O standards in a bank.
- Not available (N/A) indicates that the I/O standard is not available in the given bank.
- When used with the MCB, these signals are exempt from SSO analysis due to the known activity of the MCB switching patterns. SSO performance is validated for all MCB instances. MCB outputs can, in some cases, exceed the SSO limits.

CLB Switching Characteristics (SLICEM Only)

Table 40: CLB Switching Characteristics (SLICEM Only)

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Combinatorial Delays						
T _{ILO}	An – Dn LUT inputs to A to D outputs	0.21	0.26	0.26	0.46	ns, Max
	An – Dn LUT inputs through F7AMUX/F7BMUX to AMUX/CMUX output	0.37	0.43	0.43	0.77	ns, Max
T _{OPAB}	An – Dn LUT inputs through F7AMUX or F7BMUX and F8MUX to BMUX output	0.37	0.46	0.46	0.84	ns, Max
T _{ITO}	An – Dn LUT inputs through latch to AQ – DQ outputs	0.82	0.95	0.95	1.64	ns, Max
T _{TITO_LOGIC}	An – Dn LUT inputs to AQ – DQ outputs (latch as logic)	0.82	0.95	0.95	1.64	ns, Max
T _{OPCYA}	An LUT inputs to COUT output	0.38	0.48	0.48	0.69	ns, Max
T _{OPCYB}	Bn LUT inputs to COUT output	0.38	0.49	0.49	0.71	ns, Max
T _{OPCYC}	Cn LUT inputs to COUT output	0.28	0.33	0.33	0.55	ns, Max
T _{OPCYD}	Dn LUT inputs to COUT output	0.28	0.35	0.35	0.52	ns, Max
T _{AXCY}	AX input to COUT output	0.21	0.26	0.26	0.36	ns, Max
T _{BXCy}	BX input to COUT output	0.13	0.16	0.16	0.18	ns, Max
T _{CXCy}	CX input to COUT output	0.10	0.12	0.12	0.09	ns, Max
T _{DXCy}	DX input to COUT output	0.09	0.11	0.11	0.09	ns, Max
T _{BYP}	CIN input to COUT output	0.08	0.10	0.10	0.06	ns, Max
T _{CINA}	CIN input to AMUX output	0.21	0.22	0.22	0.47	ns, Max
T _{CINB}	CIN input to BMUX output	0.30	0.31	0.31	0.57	ns, Max
T _{CINC}	CIN input to CMUX output	0.29	0.31	0.31	0.58	ns, Max
T _{CIND}	CIN input to DMUX output	0.31	0.32	0.32	0.68	ns, Max
Sequential Delays						
T _{CKO}	Clock to AQ – DQ outputs	0.45	0.53	0.53	0.74	ns, Max
Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK						
T _{DICK} /T _{CKDI}	AX – DX input to CLK on A – D flip-flops	0.42/ 0.28	0.47/ 0.39	0.47/ 0.39	0.90/ 0.56	ns, Min
T _{CECK} /T _{CKCE}	CE input to CLK on A – D flip-flops	0.31/ –0.07	0.37/ –0.07	0.37/ –0.07	0.59/ –0.27	ns, Min
T _{SRCK} /T _{CKSR}	SR input to CLK on A – D flip-flops for XC devices	0.41/ 0.02	0.42/ 0.02	0.42/ 0.02	0.68/ –0.29	ns, Min
	SR input to CLK on A – D flip-flops for XA and XQ devices	0.41/ 0.02	N/A	0.44/ 0.02	0.68/ –0.29	ns, Min
T _{CINCK} /T _{CKCIN}	CIN input to CLK on A – D flip-flops	0.31/ –0.17	0.31/ –0.13	0.31/ –0.13	0.81/ –0.42	ns, Min
Set/Reset						
T _{RPW}	SR input minimum pulse width	0.41	0.48	0.48	1.37	ns, Min
T _{RQ}	Delay from SR input to AQ – DQ flip-flops	0.60	0.70	0.70	0.88	ns, Max
T _{CEO}	Delay from CE input to AQ – DQ flip-flops	0.60	0.65	0.65	0.90	ns, Max
F _{TOG}	Toggle frequency (for export control)	862	806	667	500	MHz

Table 47: Configuration Switching Characteristics⁽¹⁾ (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
BPI Master Flash Mode Programming Switching ⁽⁴⁾						
T _{BPICCO} ⁽⁵⁾	A[25:0], FCS_B, FOE_B, FWE_B, LDC outputs valid after CCLK falling edge	15	15	15	20	ns, Max
T _{BPIICCK}	Master BPI CCLK (output) delay	10/100	10/100	10/100	10/130	μs, Min/Max
T _{BPIDCC} /T _{BPICCD}	Setup/Hold on D[15:0] data input pins	5.0/1.0	5.0/1.0	5.0/1.0	6.0/2.0	ns, Min
SPI Master Flash Mode Programming Switching ⁽⁶⁾						
T _{SPIDCC} /T _{SPIDCCD}	DIN, MISO0, MISO1, MISO2, MISO3, Setup/Hold before/after the rising CCLK edge	5.0/1.0	5.0/1.0	5.0/1.0	7.0/1.0	ns, Min
T _{SPIICCK}	Master SPI CCLK (output) delay	0.4/7.0	0.4/7.0	0.4/7.0	0.4/10.0	μs, Min/Max
T _{SPICCM}	MOSI clock to out	13	13	13	19	ns, Max
T _{SPICCFC}	CSO_B clock to out	16	16	16	26	ns, Max
CCLK Output (Master Modes)						
T _{MCCKL}	Master CCLK clock duty cycle Low	40/60				%, Min/Max
T _{MCCKH}	Master CCLK clock duty cycle High	40/60				%, Min/Max
F _{MCCK}	Maximum frequency, serial mode (Master Serial/SPI) All devices	40	40	40	30	MHz, Max
	Maximum frequency, parallel mode (Master SelectMAP/BPI) LX9, LX16, LX25, LX25T, LX45, LX45T, LX75, and LX75T	40	40	40	25	MHz, Max
	Maximum frequency, parallel mode (Master SelectMAP/BPI) LX100 and LX100T in x8 mode, LX150, and LX150T	40	40	40	20	MHz, Max
	Maximum frequency, parallel mode (Master SelectMAP/BPI) LX100 and LX100T in x16 mode	35	35	35	20	MHz, Max
F _{MCCKTOL}	Frequency Tolerance, master mode	±50	±50	±50	±50	%
CCLK Input (Slave Modes)						
T _{SCCKL}	Slave CCLK clock minimum Low time	5	5	5	8	ns, Min
T _{SCCKH}	Slave CCLK clock minimum High time	5	5	5	8	ns, Min
USERCCLK Input						
T _{USERCCLKL}	USERCCLK clock minimum Low time	12	12	12	16	ns, Min
T _{USERCCLKH}	USERCCLK clock minimum High time	12	12	12	16	ns, Min
F _{USERCCLK}	Maximum USERCCLK frequency	40	40	40	30	MHz, Max

Notes:

- Maximum frequency and setup/hold timing parameters are for 3.3V and 2.5V configuration voltages.
- To support longer delays in configuration, use the design solutions described in [UG380: Spartan-6 FPGA Configuration User Guide](#).
- [Table 6](#) specifies the power supply ramp time.
- BPI mode is not supported in:
 - LX4, LX25, or LX25T devices
 - LX9 devices in the TQG144 package
 - LX9 or LX16 devices in the CPG196 package.
- Only during configuration, the last edge is determined by a weak pull-up/pull-down resistor in the I/O.
- Defense-grade Spartan-6Q -2Q devices configure in single default SPI Master (x1) mode at $T_j = -55^{\circ}\text{C}$. During operation and when using all other configuration functions, the minimum operating temperature is -40°C .

Clock Buffers and Networks

Table 48: Global Clock Switching Characteristics (BUFGMUX)

Symbol	Description	Devices	Speed Grade				Units
			-3	-3N	-2	-1L	
T _{GSI}	S pin Setup to I0/I1 inputs	LX devices	0.25	0.31	0.48	0.48	ns
		LXT devices	0.25	0.31	0.48	N/A	ns
T _{GIO}	BUFGMUX delay from I0/I1 to O	LX devices	0.21	0.21	0.21	0.21	ns
		LXT devices	0.21	0.21	0.21	N/A	ns
Maximum Frequency							
F _{MAX}	Global clock tree (BUFGMUX)	LX devices	400	400	375	250	MHz
		LXT devices	400	400	375	N/A	MHz

Table 49: Input/Output Clock Switching Characteristics (BUFIO2)

Symbol	Description	Devices	Speed Grade				Units
			-3	-3N	-2	-1L	
T _{BUFCO_O}	Clock to out delay from I to O	LX devices	0.67	0.82	1.09	1.50	ns
		LXT devices	0.67	0.82	1.09	N/A	ns
Maximum Frequency							
F _{MAX}	I/O clock tree (BUFIO2)	LX devices	540	525	500	300	MHz
		LXT devices	540	525	500	N/A	MHz

Table 50: Input/Output Clock Switching Characteristics (BUFIO2FB)

Symbol	Description	Devices	Speed Grade				Units
			-3	-3N	-2	-1L	
Maximum Frequency							
F _{MAX}	I/O clock tree (BUFIO2FB)	LX devices	1080	1050	950	500	MHz
		LXT devices	1080	1050	950	N/A	MHz

Table 51: Input/Output Clock Switching Characteristics (BUFPLL)

Symbol	Description	Devices	Speed Grade				Units
			-3	-3N	-2	-1L	
Maximum Frequency							
F _{MAX}	BUFPLL clock tree (BUFPLL)	LX devices	1080	1050	950	500	MHz
		LXT devices	1080	1050	950	N/A	MHz

PLL Switching Characteristics

Table 52: PLL Specification

Symbol	Description	Device ⁽¹⁾	Speed Grade				Units
			-3	-3N	-2	-1L	
F_{INMAX}	Maximum Input Clock Frequency from I/O Clock	LX devices	540	525	450	300	MHz
		LXT devices	540	525	450	N/A	MHz
	Maximum Input Clock Frequency from Global Clock	LX devices	400	400	375	250	MHz
		LXT devices	400	400	375	N/A	MHz

Table 64: Global Clock Input to Output Delay With DCM in System-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> DCM in System-Synchronous Mode.							
T _{ICKOFDCM}	Global Clock and OUTFF <i>with</i> DCM	XC6SLX4	4.23	N/A	6.11	6.60	ns
		XC6SLX9	4.23	5.17	6.11	6.60	ns
		XC6SLX16	4.28	4.57	5.34	6.36	ns
		XC6SLX25	3.95	4.18	4.59	6.91	ns
		XC6SLX25T	3.95	4.18	4.59	N/A	ns
		XC6SLX45	4.37	4.70	5.50	6.85	ns
		XC6SLX45T	4.37	4.70	5.50	N/A	ns
		XC6SLX75	3.90	4.23	4.77	6.31	ns
		XC6SLX75T	3.90	4.23	4.77	N/A	ns
		XC6SLX100	3.86	4.16	4.66	7.25	ns
		XC6SLX100T	3.90	4.16	4.66	N/A	ns
		XC6SLX150	4.03	4.33	4.83	6.63	ns
		XC6SLX150T	4.03	4.33	4.83	N/A	ns
		XA6SLX4	4.55	N/A	6.11	N/A	ns
		XA6SLX9	4.55	N/A	6.11	N/A	ns
		XA6SLX16	4.62	N/A	5.33	N/A	ns
		XA6SLX25	4.27	N/A	4.59	N/A	ns
		XA6SLX25T	4.27	N/A	4.69	N/A	ns
		XA6SLX45	4.69	N/A	5.50	N/A	ns
		XA6SLX45T	4.69	N/A	5.50	N/A	ns
		XA6SLX75	4.22	N/A	4.77	N/A	ns
		XA6SLX75T	4.22	N/A	4.77	N/A	ns
		XA6SLX100	N/A	N/A	5.34	N/A	ns
		XQ6SLX75	N/A	N/A	4.77	6.31	ns
		XQ6SLX75T	4.22	N/A	4.77	N/A	ns
		XQ6SLX150	N/A	N/A	4.96	6.63	ns
		XQ6SLX150T	4.62	N/A	4.96	N/A	ns

Notes:

- Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
- DCM output jitter is already included in the timing calculation.

Table 67: Global Clock Input to Output Delay With PLL in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> PLL in Source-Synchronous Mode.							
T _{ICKOFFLL_0}	Global Clock and OUTFF <i>with</i> PLL	XC6SLX4	5.49	N/A	7.44	8.55	ns
		XC6SLX9	5.49	6.29	7.44	8.55	ns
		XC6SLX16	5.23	5.77	6.79	8.21	ns
		XC6SLX25	5.00	5.35	6.10	8.54	ns
		XC6SLX25T	5.00	5.35	6.10	N/A	ns
		XC6SLX45	5.59	6.03	7.02	8.39	ns
		XC6SLX45T	5.59	6.03	7.02	N/A	ns
		XC6SLX75	4.96	5.41	6.22	8.32	ns
		XC6SLX75T	4.96	5.41	6.22	N/A	ns
		XC6SLX100	4.97	5.42	6.21	9.08	ns
		XC6SLX100T	5.01	5.42	6.21	N/A	ns
		XC6SLX150	4.59	5.06	5.86	8.13	ns
		XC6SLX150T	4.59	5.06	5.86	N/A	ns
		XA6SLX4	5.79	N/A	7.32	N/A	ns
		XA6SLX9	5.79	N/A	7.32	N/A	ns
		XA6SLX16	5.56	N/A	6.66	N/A	ns
		XA6SLX25	5.40	N/A	5.97	N/A	ns
		XA6SLX25T	5.40	N/A	6.07	N/A	ns
		XA6SLX45	5.89	N/A	6.90	N/A	ns
		XA6SLX45T	5.89	N/A	6.90	N/A	ns
		XA6SLX75	5.27	N/A	6.12	N/A	ns
		XA6SLX75T	5.27	N/A	6.12	N/A	ns
		XA6SLX100	N/A	N/A	6.80	N/A	ns
		XQ6SLX75	N/A	N/A	6.12	8.32	ns
		XQ6SLX75T	5.27	N/A	6.12	N/A	ns
		XQ6SLX150	N/A	N/A	5.88	8.13	ns
		XQ6SLX150T	5.21	N/A	5.88	N/A	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. PLL output jitter is included in the timing calculation.

Spartan-6 Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in Table 70 through Table 77. Values are expressed in nanoseconds unless otherwise noted.

Table 70: Global Clock Setup and Hold Without DCM or PLL (No Delay)

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVC MOS25 Standard.(1)							
T _{PSND} / T _{PHND}	No Delay Global Clock and IFF(3) without DCM or PLL	XC6SLX4	0.10/1.56	N/A	0.10/1.83	0.07/2.54	ns
		XC6SLX9	0.10/1.56	0.10/1.57	0.10/1.84	0.07/2.54	ns
		XC6SLX16	0.12/1.42	0.12/1.48	0.12/1.64	0.13/2.19	ns
		XC6SLX25	0.18/1.64	0.18/1.75	0.18/1.99	0.11/2.57	ns
		XC6SLX25T	0.18/1.64	0.18/1.75	0.18/1.99	N/A	ns
		XC6SLX45	−0.08/1.80	−0.08/1.95	−0.08/2.27	−0.17/2.74	ns
		XC6SLX45T	−0.08/1.80	−0.08/1.95	−0.08/2.27	N/A	ns
		XC6SLX75	0.13/1.81	0.13/2.06	0.13/2.27	−0.12/3.30	ns
		XC6SLX75T	0.13/1.81	0.13/2.06	0.13/2.27	N/A	ns
		XC6SLX100	−0.14/2.03	−0.14/2.24	−0.14/2.56	−0.17/3.44	ns
		XC6SLX100T	−0.14/2.03	−0.14/2.24	−0.14/2.56	N/A	ns
		XC6SLX150	−0.24/2.42	−0.24/2.74	−0.24/2.95	−0.60/3.75	ns
		XC6SLX150T	−0.24/2.42	−0.24/2.74	−0.24/2.95	N/A	ns
		XA6SLX4	0.10/1.57	N/A	0.10/1.84	N/A	ns
		XA6SLX9	0.10/1.57	N/A	0.10/1.84	N/A	ns
		XA6SLX16	0.12/1.43	N/A	0.12/1.64	N/A	ns
		XA6SLX25	0.18/1.65	N/A	0.18/1.99	N/A	ns
		XA6SLX25T	0.18/1.65	N/A	0.18/1.99	N/A	ns
		XA6SLX45	−0.08/1.82	N/A	−0.08/2.27	N/A	ns
		XA6SLX45T	−0.08/1.82	N/A	−0.08/2.27	N/A	ns
		XA6SLX75	0.13/2.02	N/A	0.13/2.32	N/A	ns
		XA6SLX75T	0.13/2.02	N/A	0.13/2.32	N/A	ns
		XA6SLX100	N/A	N/A	0.10/2.51	N/A	ns
		XQ6SLX75	N/A	N/A	0.13/2.32	−0.12/3.30	ns
		XQ6SLX75T	0.13/2.02	N/A	0.13/2.32	N/A	ns
		XQ6SLX150	N/A	N/A	−0.24/2.95	−0.60/3.75	ns
		XQ6SLX150T	−0.24/2.74	N/A	−0.24/2.95	N/A	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input Flip-Flop or Latch.

Table 71: Global Clock Setup and Hold Without DCM or PLL (Default Delay)

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard. ⁽¹⁾							
T _{PSFD} / T _{PHFD}	Default Delay ⁽²⁾ Global Clock and IFF ⁽³⁾ without DCM or PLL	XC6SLX4	0.66/1.17	N/A	1.05/0.79	2.09/1.05	ns
		XC6SLX9	0.66/1.17	0.75/1.17	1.05/1.17	2.09/1.05	ns
		XC6SLX16	0.87/1.16	0.93/1.16	0.96/1.16	1.86/1.06	ns
		XC6SLX25	0.68/0.77	0.81/0.81	0.87/0.82	2.21/1.33	ns
		XC6SLX25T	0.68/0.77	0.81/0.81	0.87/0.82	N/A	ns
		XC6SLX45	0.40/1.05	0.42/1.17	0.64/1.20	1.61/1.67	ns
		XC6SLX45T	0.40/1.05	0.42/1.17	0.64/1.20	N/A	ns
		XC6SLX75	0.41/1.11	0.41/1.13	0.80/1.14	1.23/1.82	ns
		XC6SLX75T	0.41/1.11	0.41/1.13	0.80/1.14	N/A	ns
		XC6SLX100	0.39/1.12	0.39/1.23	0.39/1.28	1.13/1.94	ns
		XC6SLX100T	0.39/1.12	0.39/1.23	0.39/1.28	N/A	ns
		XC6SLX150	0.23/1.54	0.23/1.62	0.23/1.62	1.14/2.05	ns
		XC6SLX150T	0.23/1.54	0.23/1.62	0.23/1.62	N/A	ns
		XA6SLX4	0.73/1.18	N/A	1.05/0.80	N/A	ns
		XA6SLX9	0.73/1.18	N/A	1.05/0.80	N/A	ns
		XA6SLX16	0.90/1.20	N/A	0.96/0.75	N/A	ns
		XA6SLX25	0.70/0.81	N/A	0.87/0.91	N/A	ns
		XA6SLX25T	0.76/0.81	N/A	1.03/0.91	N/A	ns
		XA6SLX45	0.40/1.06	N/A	0.64/1.20	N/A	ns
		XA6SLX45T	0.40/1.06	N/A	0.64/1.20	N/A	ns
		XA6SLX75	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XA6SLX75T	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XA6SLX100	N/A	N/A	0.86/1.55	N/A	ns
		XQ6SLX75	N/A	N/A	0.80/1.18	1.23/1.82	ns
		XQ6SLX75T	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XQ6SLX150	N/A	N/A	0.28/1.57	1.14/2.05	ns
		XQ6SLX150T	0.28/1.78	N/A	0.28/1.57	N/A	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- Default delay uses IODELAY2 tap 0.
- IFF = Input Flip-Flop or Latch.

Table 74: Global Clock Setup and Hold With PLL in System-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVC MOS25 Standard.(1)							
T _{PSPLL} / T _{PHPLL}	No Delay Global Clock and IFF(2) with PLL in System-Synchronous Mode	XC6SLX4	1.37/0.25	N/A	1.52/0.41	2.07/0.69	ns
		XC6SLX9	1.37/0.21	1.48/0.21	1.52/0.26	2.07/0.69	ns
		XC6SLX16	1.33/−0.03	1.53/−0.02	1.60/−0.02	1.57/0.48	ns
		XC6SLX25	1.65/0.28	1.71/0.28	1.91/0.28	2.44/0.76	ns
		XC6SLX25T	1.65/0.28	1.71/0.28	1.91/0.28	N/A	ns
		XC6SLX45	1.55/0.18	1.64/0.18	1.75/0.18	2.02/0.90	ns
		XC6SLX45T	1.55/0.18	1.64/0.18	1.75/0.18	N/A	ns
		XC6SLX75	1.77/0.21	1.89/0.21	2.13/0.21	2.46/0.53	ns
		XC6SLX75T	1.77/0.21	1.89/0.21	2.13/0.21	N/A	ns
		XC6SLX100	1.44/0.32	1.52/0.32	1.70/0.32	1.78/0.86	ns
		XC6SLX100T	1.44/0.32	1.52/0.32	1.70/0.32	N/A	ns
		XC6SLX150	1.39/0.49	1.48/0.49	1.67/0.49	1.94/0.94	ns
		XC6SLX150T	1.39/0.49	1.48/0.49	1.67/0.49	N/A	ns
		XA6SLX4	1.61/0.10	N/A	1.64/0.28	N/A	ns
		XA6SLX9	1.61/0.10	N/A	1.64/0.28	N/A	ns
		XA6SLX16	1.89/−0.08	N/A	1.72/−0.08	N/A	ns
		XA6SLX25	1.85/0.16	N/A	2.08/0.16	N/A	ns
		XA6SLX25T	1.85/0.16	N/A	2.17/0.16	N/A	ns
		XA6SLX45	1.58/0.07	N/A	1.87/0.03	N/A	ns
		XA6SLX45T	1.58/0.07	N/A	1.87/0.03	N/A	ns
		XA6SLX75	1.80/0.06	N/A	2.25/0.06	N/A	ns
		XA6SLX75T	1.80/0.06	N/A	2.25/0.06	N/A	ns
		XA6SLX100	N/A	N/A	2.34/0.14	N/A	ns
		XQ6SLX75	N/A	N/A	2.25/0.06	2.46/0.53	ns
		XQ6SLX75T	1.80/0.06	N/A	2.25/0.06	N/A	ns
		XQ6SLX150	N/A	N/A	1.79/0.37	1.94/0.94	ns
		XQ6SLX150T	1.43/0.37	N/A	1.79/0.37	N/A	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include PLL CLKOUT0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 76: Global Clock Setup and Hold With DCM and PLL in System-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard. ⁽¹⁾							
T _{PSDCMPLL} / T _{PHDCMPLL}	No Delay Global Clock and IFF ⁽²⁾ with DCM in System-Synchronous Mode and PLL in DCM2PLL Mode.	XC6SLX4	1.16/0.49	N/A	1.39/0.49	2.36/0.59	ns
		XC6SLX9	1.16/0.44	1.37/0.44	1.39/0.44	2.36/0.59	ns
		XC6SLX16	1.44/−0.08	1.49/−0.04	1.62/−0.04	2.06/0.55	ns
		XC6SLX25	1.52/0.42	1.65/0.42	1.83/0.42	2.52/0.43	ns
		XC6SLX25T	1.52/0.42	1.65/0.42	1.83/0.42	N/A	ns
		XC6SLX45	1.54/0.39	1.59/0.39	1.75/0.39	2.48/0.76	ns
		XC6SLX45T	1.54/0.39	1.59/0.39	1.75/0.39	N/A	ns
		XC6SLX75	1.72/0.41	1.80/0.41	1.99/0.41	2.60/0.75	ns
		XC6SLX75T	1.72/0.41	1.80/0.41	1.99/0.41	N/A	ns
		XC6SLX100	1.34/0.51	1.46/0.51	1.64/0.51	2.12/0.90	ns
		XC6SLX100T	1.34/0.51	1.46/0.51	1.64/0.51	N/A	ns
		XC6SLX150	1.30/0.60	1.40/0.60	1.55/0.60	2.57/0.97	ns
		XC6SLX150T	1.30/0.60	1.40/0.60	1.55/0.60	N/A	ns
		XA6SLX4	1.58/0.37	N/A	1.58/0.37	N/A	ns
		XA6SLX9	1.58/0.37	N/A	1.58/0.37	N/A	ns
		XA6SLX16	2.67/0.35	N/A	2.67/0.17	N/A	ns
		XA6SLX25	1.74/0.27	N/A	1.95/0.27	N/A	ns
		XA6SLX25T	1.74/0.27	N/A	2.03/0.27	N/A	ns
		XA6SLX45	1.58/0.29	N/A	1.87/0.29	N/A	ns
		XA6SLX45T	1.58/0.29	N/A	1.87/0.29	N/A	ns
		XA6SLX75	1.74/0.24	N/A	2.11/0.24	N/A	ns
		XA6SLX75T	1.74/0.24	N/A	2.11/0.24	N/A	ns
		XA6SLX100	N/A	N/A	2.64/0.82	N/A	ns
		XQ6SLX75	N/A	N/A	2.11/0.24	2.60/0.75	ns
		XQ6SLX75T	1.74/0.24	N/A	2.11/0.24	N/A	ns
		XQ6SLX150	N/A	N/A	1.67/0.70	2.57/0.97	ns
		XQ6SLX150T	1.50/0.70	N/A	1.67/0.70	N/A	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include CMT jitter; DCM CLK0 driving PLL, PLL CLKOUT0 driving BUFG.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 77: Global Clock Setup and Hold With DCM and PLL in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Example Data Input Set-Up and Hold Times Relative to a Forwarded Clock Input Pin, ⁽¹⁾ Using DCM, PLL, and Global Clock Buffer for the LVCMOS25 standard.							
T _{PSDCMPLL_0} / T _{PHDCMPLL_0}	No Delay Global Clock and IFF ⁽²⁾ with DCM in Source-Synchronous Mode and PLL in DCM2PLL Mode.	XC6SLX4	0.43/1.07	N/A	0.43/1.43	1.10/1.67	ns
		XC6SLX9	0.43/1.03	0.45/1.14	0.45/1.43	1.10/1.67	ns
		XC6SLX16	0.74/0.93	0.74/1.12	0.74/1.21	0.77/1.35	ns
		XC6SLX25	0.67/1.02	0.76/1.11	0.84/1.18	1.23/1.46	ns
		XC6SLX25T	0.67/1.02	0.76/1.11	0.84/1.18	N/A	ns
		XC6SLX45	0.65/0.99	0.65/1.04	0.71/1.12	1.18/1.58	ns
		XC6SLX45T	0.65/1.00	0.65/1.04	0.71/1.12	N/A	ns
		XC6SLX75	0.86/1.01	0.88/1.06	0.94/1.14	1.29/1.67	ns
		XC6SLX75T	0.86/1.01	0.88/1.06	0.94/1.14	N/A	ns
		XC6SLX100	0.50/1.10	0.56/1.10	0.61/1.17	0.84/2.24	ns
		XC6SLX100T	0.50/1.10	0.56/1.10	0.61/1.17	N/A	ns
		XC6SLX150	0.45/1.28	0.47/1.28	0.52/1.28	1.27/1.56	ns
		XC6SLX150T	0.45/1.28	0.47/1.28	0.52/1.28	N/A	ns
		XA6SLX4	0.74/1.00	N/A	0.74/1.43	N/A	ns
		XA6SLX9	0.74/1.00	N/A	0.74/1.43	N/A	ns
		XA6SLX16	1.81/1.15	N/A	1.81/1.03	N/A	ns
		XA6SLX25	0.89/1.01	N/A	0.96/1.05	N/A	ns
		XA6SLX25T	0.89/1.01	N/A	1.04/1.15	N/A	ns
		XA6SLX45	0.69/0.95	N/A	0.83/0.96	N/A	ns
		XA6SLX45T	0.69/0.95	N/A	0.83/0.96	N/A	ns
		XA6SLX75	0.88/0.94	N/A	1.06/0.96	N/A	ns
		XA6SLX75T	0.88/0.94	N/A	1.06/0.96	N/A	ns
		XA6SLX100	N/A	N/A	1.55/1.33	N/A	ns
		XQ6SLX75	N/A	N/A	1.06/0.96	1.29/1.67	ns
		XQ6SLX75T	0.88/0.94	N/A	1.06/0.96	N/A	ns
		XQ6SLX150	N/A	N/A	0.64/1.30	1.27/1.56	ns
		XQ6SLX150T	0.58/1.30	N/A	0.64/1.30	N/A	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. The timing values were measured using the fine-phase adjustment feature of the DCM. These measurements include CMT jitter; DCM CLK0 driving PLL, PLL CLKOUT0 driving BUFG. Package skew is not included in these measurements.
- IFF = Input Flip-Flop

Revision History

The following table shows the revision history for this document.

Date	Version	Description of Revisions
06/24/09	1.0	Initial Xilinx release.
08/26/09	1.1	Added V_{FS} to Table 1 and Table 2 . Added R_{FUSE} to Table 2 . Added XC6SLX75 and XC6SLX75T to V_{BATT} and I_{BATT} in Table 1 , Table 2 , and Table 4 . Corrected the quiescent supply current for the XC6SLX4 in Table 5 . Updated Table 11 . Removed DV_{PPIN} from Figure 2 . Removed $F_{PCIECORE}$ from Table 24 and added values to $F_{PCIEUSER}$. Added more networking applications to Table 25 . Updated values for $T_{SUSPENDLOW_AWAKE}$, $T_{SUSPEND_ENABLE}$, and T_{SCP_AWAKE} in Table 46 . Numerous changes to Table 47 , page 54 including the addition of new values to various specifications, revising the $T_{SMCKCSO}$ description, and changing the units of T_{POR} . Also, removed <i>Dynamic Reconfiguration Port (DRP) for DCM and PLL Before and After DCLK</i> section from Table 47 and updated all the notes. In Table 52 , added to F_{INMAX} , revised F_{OUTMAX} , and removed PLL Maximum Output Frequency for BUFIO2. Revised values for DCM_DELAY_STEP in Table 54 . Updated CLKIN_FREQ_FX values in Table 55 .
01/04/10	1.2	Added -4 speed grade to entire document. Updated speed specification of -4, -3, -2 speed grades to version 1.03. Added -1L speed grade numbers per speed specification 1.00. Updated T_{SOL} in Table 1 . Added -1L rows for LVCMOS12, LVCMOS15, and LVCMOS18 in Table 9 . Revised much of the detail in GTP Transceiver Specifications in Table 12 through Table 23 . Added -2 data to Table 25 . Updated F_{MAX} in Table 44 . Updated descriptions for T_{DNACKL} and T_{DNACKH} in Table 45 and revised values for all parameters. Removed $T_{INITADDR}$ from Table 47 and added new data. Updated values in Table 48 through Table 62 . Added Table 51 (BUFPLL) and Table 57 (DCM_CLKGEN). Removed $T_{LOCKMAX}$ note from Table 52 . Updated note 3 in Table 53 . In Table 79 : removed XC6SLX75CSG324 and XC6SLX75TCSG324; added XC6SLX75FG(G)484 and XC6SLX75FG(G)484.
02/22/10	1.3	Production release of XC6SLX16 -2 speed grade devices. The changes to Table 26 and Table 27 includes updating this data sheet to the data in ISE v11.5 software with speed specification v1.06. Updated maximum of V_{IN} and V_{TS} and note 2 in Table 1 . In Table 2 , changed V_{IN} , added I_{IN} and note 5, revised notes 1, 6, and 7, and added note 8 to R_{FUSE} . In Table 4 , removed previous note 1 and added data to I_{RPU} , I_{RPD} , and I_{BATT} , changed C_{IN} , added R_{DT} and R_{IN_TERM} , and added note 2 and 3. Updated V_{CCO2} in Table 6 . Added Table 7 and Table 8 . Removed PCI66_3 from Table 9 . Updated PCI33_3 and I2C in Table 9 . Updated the description of Table 11 . Completely updated Table 25 . Updated Table 28 including adding values for PCI33_3. Updated V_{REF} value for HSTL_III_18 in Table 31 . Updates missing V_{REF} values in Table 32 . Added Simultaneously Switching Outputs , page 36 . Removed T_{GSRQ} and T_{RPW} from Table 35 and Table 36 . Also removed T_{DOQ} from Table 36 . Removed T_{ISDO_DO} and note 1 from Table 37 . Removed T_{OSCK_S} and combinatorial section from Table 38 . In Table 39 , removed T_{IODDO_T} and added new tap parameters and note 2. In Table 40 , Table 41 , and Table 42 , made typographical edits and removed notes. Removed clock CLK section in Table 41 . Removed clock CLK section and T_{REG_MUX} and T_{REG_M31} in Table 42 . Added block RAM F_{MAX} values to Table 43 . Updated values and added note 2 to Table 45 . Added values to Table 46 and removed note 1. Numerous changes to Table 47 . Completely updated Table 57 . Revised data in Table 62 . Removed note 3 from Table 71 . Added values to Table 79 . Added data to Table 80 and Table 81 .
03/10/10	1.4	Production release of XC6SLX45 -2 speed grade devices, which includes changes to Table 26 and Table 27 updating this data sheet to the data in ISE v11.5 software with speed specification v1.07. Fixed R_{IN_TERM} description in Table 4 . Added PCI66_3 to Table 7 and replaced note 1. Corrected note 1 and the V, Max for TMDS_33 in Table 8 . In Table 10 , added note 1 to LVPECL_33 and TMDS_33. Also updated specifications for TMDS_33. Updated the GTP Transceiver Specifications section including adding values to Table 16 , Table 17 , and Table 20 through Table 23 . Added PCI66_3 back into Table 9 , Table 28 , Table 31 , Table 32 , and Table 34 . Updated note 3 on Table 32 . In Table 34 , corrected some typographical errors and fixed SSO limits for bank1/3 in FG(G)484 package. Corrected T_{OSCK_OCE} in Table 38 . In Table 57 , updated CLKFX_FREEZE_VAR and CLKFX_FREEZE_TEMP_SLOPE and added typical values to $T_{CENTER_LOW_SPREAD}$ and $T_{CENTER_HIGH_SPREAD}$. Updated and added values to Table 63 through Table 78 , and Table 81 . In Table 79 , revised the XC6SLX16-CSG324 and the XC6SLX45-CSG484 and FG(G)484 values.

Date	Version	Description of Revisions
01/10/11	1.11	Production release of XC6SLX4 and XC6SLX9 in the specific speed grades listed in Table 26 and Table 27 using ISE v12.4 software with speed specification v1.15 for the -4, -3, -3N, and -2 speed grades. Added note 3 to Table 27. Also updated the -1L speed grade requirements to ISE v12.4 software with speed specification v1.06. Revised -3N definition throughout the document. Added note 4 to Table 2 and updated note 5. Added information on V_{CCINT} to note 1 in Table 5. Updated Networking Applications -3 values in Table 25 to match improvements made in ISE v12.4. In Table 28, added note 1 and revised the T_{IOTP} values for LVDS_33, LVDS_25, MINI_LVDS_33, MINI_LVDS_25, RSDS_33, RSDS_25, TMDS_33, PPDS_33, and PPDS_25. Added note 3 to Table 55.
02/11/11	1.12	As described in XCEN11008: Product Discontinuation Notice For Spartan-6 LXT -4 Devices, the -4 speed specifications have been discontinued. As outlined in page 2 of the XCN, designers currently using -4 speed specifications should rerun timing analysis using the new -3 speed specifications before moving to a replacement device. Updated the networking applications section of Table 25. Updated -2 speed specifications throughout document and added note 3 to Table 27 advising designers to use the -2 speed specification update (v1.17) with the ISE 12.4 software patch. Added F_{CLKDIV} to Table 37 and Table 38. Updated note 2 in Table 39. Updated units for $T_{SMCKCSO}$ and T_{BPICCO} in Table 47. Updated -1L in Table 71. Removed Note 2: <i>Package delay information is available for these device/package combinations. This information can be used to deskew the package</i> from Table 79.
03/31/11	2.0	Production release of XC6SLX45 in the -1L speed grades listed in Table 26 and Table 27 using ISE v13.1 software with -1L speed specification v1.06. In Table 39, removed values in the -1L column and added note 3 as IODELAY2 only supports Tap0 for lower-power devices. Updated copyright page 1 and Notice of Disclaimer.
05/20/11	2.1	Production release of XC6SLX100 and XC6SLX150 in the specific speed grades listed in Table 26 and Table 27 using ISE v13.1 software with -1L speed specification v1.06. Updated Table 27 and Note 7 with changes per XCEN11012: Speed File Change for -3N Devices. Revised Switching Characteristics section for speed specifications: v1.18 for -3, -3N, and -2; including improvements in Table 73 through Table 77 and Table 81. Removed <i>Memory Controller Block</i> from the performance heading in Table 2 and revised Note 2. In Table 4, added Note 1 to C_{IN} and updated the description of R_{IN_TERM}. Updated Note 1 in Table 5. Updated Note 1 of Table 7. In Table 25, added and removed -1L specifications, increased the standard performance DDR3 specifications, removed the extended performance DDR3 row and updated Note 3 and Note 4. Clarified the introductory information for Table 28 and Table 30. In Table 32: Revised V_{MEAS} value for LVCMOS12; revised V_{REF} for LVDS_25, LVDS_33, BLVDS_25, MINI_LVDS_25, MINI_LVDS_33, RSDS_25, and RSDS_33; revised R_{REF} for BLVDS_25 and TMDS_33; and added Note 4 and Note 5. Updated Note 2 and Note 3 in Table 39. In Table 47, revised the values and description of T_{POR} including adding Note 3. Also in Table 47, augmented the description and added specifications for F_{RBCKK} and removed XC6SLX4 from F_{MCCCK} (maximum frequency, parallel mode (Master SelectMAP/BPI)). Added BUFGMUX to Table 48 title. Added Table 50. In Table 52, revised specifications for $T_{EXTFVAR}$ and $F_{INJITTER}$. In Table 54 removed the 5 MHz < CLKIN_FREQ_DLL parameter in the LOCK_DLL description. In both Table 56 and Table 57, removed the 5 MHz < F_{CLKIN} parameter in the LOCK_FX description. In Table 58, updated description for PSCLK_FREQ and PSCLK_PULSE. Revised title and symbol of Table 70, added new speed specifications for -1L, and added Note 2. Added Table 71.
07/11/11	2.2	Added the Automotive XA Spartan-6 and Defense-grade Spartan-6Q devices to all appropriate tables while sometimes removing the XC6S nomenclature. Added expanded temperature range (Q) to all appropriate tables. Updated T_{SOL} packages in Table 1. Added R_{OUT_TERM} to Table 4. Updated Note 2 on Table 13. Production release of the XC6SLX4, XC6SLX9, XC6SLX16, XC6SLX25, XC6SLX75, XQ6SLX75, and XQ6SLX150 in Table 26 and Table 27 using ISE v13.2 software with -1L speed specification v1.07. Production release of the XA6SLX16, XA6SLX25T, XA6SLX45, XA6SLX45T, XQ6SLX75, XQ6SLX75T, XQ6SLX150, and XQ6SLX150T in Table 26 and Table 27 using ISE v13.2 software with -2 and -3 speed specification v1.19. Added Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices(1). Updated CS(G)484 from CSG484 throughout data sheet. Clarified Note 3 in Table 39.
08/08/11	2.3	Production release of the XA6SLX25, XA6SLX75, and XA6SLX75T in Table 26 and Table 27 using ISE v13.2 software with -2 and -3 speed specification v1.19.